

NCMC-9 Discussion Session, 04-24-06  
Flipchart Notes

1. Scope of Metrology Needs
  - a. All Aspects
  - b. Formulation
    - i. Raw Materials
    - ii. New Products
  - c. Combi for initial screening “Sweet Spot”
  - d. Basic R&D
  - e. Nanostructure???
  - f. Variables—mascara example
  - g. Industry/Disruptive Technology
  - h. Sample Preparation
  - i. Quality Control
  - j. Exfoliation Rates
  - k. Bottlenecks
    - i. Sample Preparation
    - ii. Huge Backlogs
    - iii. Kinetics
    - iv. Troubleshooting
    - v. Measurement
    - vi. Magnitude of Size/Scale (Reduction)
2. Key Materials Properties
  - a. Nano
  - b. Individual Domain
  - c. Degree of Exfoliation
  - d. Starting Material Quality
    - i. Carbon Nanotubes
  - e. Size, Shape, Composition
    - i. Chemical Analysis & Composition
  - f. Rheology (Complex)
    - i. Relation to Performance
    - ii. Wide Range
  - g. Stability
  - h. Light Scattering
  - i. Zeta Potential
  - j. Dispersion
  - k. Surfaces & Interfaces
    - i. Composition & Distribution
    - ii. Identify Properties
    - iii. Repeatability
    - iv. HT as a Reductionist Method
    - v. Standardized Nomenclature
    - vi. Bio Properties

1. Test Format
  - i. Films
  - ii. Marongoni Effects
  - iii. Reliability
  - iv. Multifunctional Materials & Measurements Correlated
3. Key Test Methods
  - a. TEM
    - i. Structure
    - ii. Internal Particle Structure
    - iii. Fluorescence (X-Ray)
    - iv. Sample
  - b. AFM
    - i. Sample (In-Situ Measurements)
    - ii. Advance Modes – Considering
    - iii. Integration
    - iv. Nanoindentation
      1. Defects
      2. Reproducibility
  - c. FESEN
    - i. Surface Structure
    - ii. Sample Preparation & Analysis
  - d. Scattering
    - i. Link to Rheology
    - ii. Rate of Determining Step (Not HT Yet)
    - iii. X-Ray
      1. High-Throughput, Automated Platform
      2. Diffraction
      3. SAXS (Sparsely Used)
    - iv. Surface Roughness
  - e. Spectroscopic
    - i. XRF
    - ii. RAMAN
    - iii. UV-VIS
    - iv. Magnetic (SQUID)
    - v. Fluorescence
    - vi. IR
    - vii. Microscopy
  - f. Measurement Selection
    - i. Guidelines
  - g. Sounds/Acoustics
    - i. Case-by-Case
    - ii. Stability
    - iii. Quantitative Challenge
    - iv. Multiple Frequencies
    - v. Production Control

- h. Electrical/Thermal Properties
  - i. Dielectric/Conduction
  - ii. Application Specific
  - iii. Reliable Sample Preparation
- i. High-Throughput
  - i. Libraries – Quality
  - ii. Deconvoluting Factors (Artifacts)
    - 1. Film Thickness
  - iii. Sample & Combi Prep
  - iv. Screening Quality
  - v. Quality is more important than Data
- j. Rheology (Complex) < 15 ml, Melts